Application/Control No. Applicant(s)/Patent Under Reexamination 10/777,026 KAWAGUCHI ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 1765 Binh X. Tran **U.S. PATENT DOCUMENTS** Document Number Date Classification Country Code-Number-Kind Code Name MM-YYYY US-6,562,713 05-2003 Belyansky et al. 438/631 Α 10-2000 В US-6,133,102 Wu, Shye-Lin 438/276 С US-US-D US-Е US-F US-G US-Н USı US-J US-Κ US-US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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